

Notice of References Cited	Application/Control No. 10/524,894		Applicant(s)/Patent Under Reexamination KNAPP ET AL.	
	Examiner Alexander O. Williams		Art Unit 2826	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,775,901 B1	08-2004	Lee et al.	29/602.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	WO 00/10179	02-2000	WO	Lee et al.	
	O	6-140451	05-1994	Japan		
	P	10-289921	10-1998	Japan	Yakida	
	Q	EP 1 202 296 A1	05-2002	Europe	Van Schuylenberger et al.	
	R					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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